L	Hits	Search Text	DB	Time stamp
Number	:			
1	27	714/719.ccls. and decod\$ and MUX	USPAT;	2004/08/16
			US-PGPUB;	11:03
			EPO; JPO;	
•			DERWENT;	
		·	IBM_TDB	
2	27	714/719.ccls. and decod\$ and MUX and	USPAT;	2004/08/16
		select	US-PGPUB;	11:04
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
3	24	714/719.ccls. and decod\$ and MUX and	USPAT;	2004/08/16
		select and compare	US-PGPUB;	13:24
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
8	318032	(compared comparison comparing compare)	USPAT;	2004/08/16
		same (memory store storage)	US-PGPUB;	13:25
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
9	75535	(compared comparison comparing compare)	USPAT;	2004/08/16
		same (memory store storage) same result	US-PGPUB;	13:25
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
10	44980	(result with (compared comparison	USPAT;	2004/08/16
		comparing compare)) same (memory store	US-PGPUB;	13:26
		storage)	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
11	25182	(result with (compared comparison	USPAT;	2004/08/16
		comparing compare)) with (memory store	US-PGPUB;	13:26
		storage)	EPO; JPO;	(3)
			DERWENT;	
4.0			IBM_TDB	2004/20/42
12	1464	(result with (compared comparison	USPAT;	2004/08/16
		comparing compare)) with (memory store	US-PGPUB;	13:27
		storage) and 714/\$.ccls.	EPO; JPO;	
			DERWENT;	
42	407	(result with (compared comparison	IBM_TDB USPAT;	2004/08/16
13	127	(result with (compared comparison comparing compare)) with (memory store	US-PGPUB;	13:27
		storage) and 714/719.ccls.	EPO; JPO;	13.21
		Storage) and / 14// 15.0018.	DERWENT;	
			IBM_TDB	
AC	99	(result with (compared comparison	USPAT	2004/08/16
16	99	comparing compare) with (memory store	JOFAI	13:27
	1	comparing compare), with (memory store	1	13.21

-	227474	memory and (test testing tested tester)	USPAT;	2004/08/10
			US-PGPUB;	16:39
			EPO; JPO;	
		·	DERWENT;	
			IBM_TDB	
-	147147	memory and (test testing tested tester) and	USPAT;	2004/08/09
		(compare comparing comparison compared)	US-PGPUB;	11:32
			EPO; JPO;	
Ĭ			DERWENT;	
			IBM_TDB	
_	122722	memory and (test testing tested tester) and	USPAT;	2004/08/09
	}	(compare comparing comparison compared)	US-PGPUB;	13:45
		and (select selection selector selecting	EPO; JPO;	
		selected)	DERWENT;	
		00.00.00.0	IBM_TDB	
_	983	memory and (test testing tested tester) and	USPAT;	2004/08/09
		(compare comparing comparison compared)	US-PGPUB;	11:34
		and (select selection selector selecting	EPO; JPO;	
		selected) and (714/718.ccls. 714/719.ccls.)	DERWENT;	
		selected, and (7147) follows:	IBM_TDB	
1_	455	memory and (test testing tested tester) and	USPAT;	2004/08/09
-	133	(compare comparing comparison compared)	US-PGPUB;	11:41
		and (select selection selector selecting	EPO; JPO;	11.41
		selected) and (714/718.ccls. 714/719.ccls.)	DERWENT;	
		and (hold holding held)	IBM_TDB	
	127	memory and (test testing tested tester) and	USPAT;	2004/08/09
-	121		US-PGPUB;	13:30
		(compare comparing comparison compared) and (select selection selector selecting	EPO; JPO;	13:30
		selected) and (714/718.ccls. 714/719.ccls.)	DERWENT;	
		and ((hold holding held) same(compare	IBM_TDB	
			IDM_IDD	
	192	comparing comparison compared))	USPAT;	2004/08/09
-	192	(britt harris).xa. and compare	US-PGPUB;	13:31
			1	13:31
			EPO; JPO; DERWENT;	
		*	IBM_TDB	
	3.4	(build hamis) we and samples and	USPAT;	2004/08/09
-	34	(britt harris).xa. and compare and	US-PGPUB;	13:38
	ŀ	714/\$.cels.	•	13:30
			EPO; JPO;	
			DERWENT;	
		0.244 h	IBM_TDB	2004/00/00
•	30	(britt harris).xa. and memory and parallel	USPAT;	2004/08/09
		and 714/\$.ccls.	US-PGPUB;	13:44
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	0004/05/45
-	1123	memory and (test testing tested tester) and	USPAT;	2004/08/12
		(compare comparing comparison compared)	US-PGPUB;	17:41
		and (select selection selector selecting	EPO; JPO;	
		selected) and ((compare comparing	DERWENT;	
		comparison compared) with (each other))	IBM_TDB_	

	258	memory and (test testing tested tester) and	USPAT;	2004/08/09
-	236	(compare comparing comparison compared)	US-PGPUB;	13:47
		and (select selection selector selecting	EPO; JPO;	
		selected) and ((compare comparing	DERWENT;	
		comparison compared) with (each other))	IBM_TDB	
		and ((compare comparing comparison		
		compared) with (write expected original))		
 	296	memory and (test testing tested tester) and	USPAT;	2004/08/09
-	250	(compare comparing comparison compared)	US-PGPUB;	13:47
		and (select selection selector selecting	EPO; JPO;	IJi4/
		•	DERWENT;	
		selected) and ((compare comparing	· ·	
		comparison compared) with (each other))	IBM_TDB	
		and ((compare comparing comparison		
		compared) with (write written expected		
		original))		2004/08/20
-	277	memory and (test testing tested tester) and	USPAT;	2004/08/09
		(compare comparing comparison compared)	US-PGPUB;	13:49
		and (select selection selector selecting	EPO; JPO;	
		selected) and ((compare comparing	DERWENT;	
		comparison compared) with (each other))	IBM_TDB	
		and ((compare comparing comparison		
		compared) with (write written expected		
		original)) and (processor processing		
		microprocessor CPU)		
-	277	memory and (test testing tested tester) and	USPAT;	2004/08/10
		(compare comparing comparison compared)	US-PGPUB;	13:06
		and (select selection selector selecting	EPO; JPO;	
		selected) and ((compare comparing	DERWENT;	
		comparison compared) with (each another	IBM_TDB	
		other)) and ((compare comparing	· `	*
		comparison compared) with (write written		
		expected original)) and (processor		
		processing microprocessor CPU)		
-	34442	parallel with (test testing tester tested)	USPAT;	2004/08/10
			US-PGPUB;	13:06
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	3160	parallel with (test testing tester tested)	USPAT;	2004/08/10
		same (memory RAM ROM SRAM DRAM	US PGPUB,	13:08
		PROM)	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	1860	parallel with (test testing tester tested)	USPAT;	2004/08/10
		same (memory RAM ROM SRAM DRAM	US-PGPUB;	13:35
1		PROM) and (semiconductor IC)	EPO; JPO;	
	1		DERWENT;	
			IBM_TDB	

parallel with (test testing tester tested)	USPAT;	2004/08/10
same (memory RAM ROM SRAM DRAM	US-PGPUB;	13:35
PROM) and (semiconductor IC) and ((test	EPO; JPO;	
testing tester tested) same (memory RAM	DERWENT;	
ROM SRAM DRAM PROM) and	IBM_TDB	
(semiconductor IC)).ab.		
parallel with (test testing tester tested)	USPAT;	2004/08/10
same (memory RAM ROM SRAM DRAM	US-PGPUB;	13:36
PROM) and (semiconductor chip circuit IC)	EPO; JPO;	
and ((test testing tester tested) same	DERWENT;	
(memory RAM ROM SRAM DRAM PROM)	IBM_TDB	
and (semiconductor chip circuit IC)).ab.		
parallel with (test testing tester tested)	USPAT;	2004/08/10
same (memory RAM ROM SRAM DRAM	US-PGPUB;	16:42
PROM) and (semiconductor chip circuit IC)	EPO; JPO;	
and ((test testing tester tested) same	DERWENT;	
(memory RAM ROM SRAM DRAM PROM)	IBM_TDB	
and (semiconductor chip circuit IC)).ab. and		
((compare comparing comparison		
compared) with (output result))		
parallel with (test testing tester tested)	USPAT;	2004/08/10
same (memory RAM ROM SRAM DRAM	US-PGPUB;	16:41
PROM) and (semiconductor chip circuit IC)	EPO; JPO;	
and ((test testing tester tested) same	DERWENT;	
(memory RAM ROM SRAM DRAM PROM)	IBM_TDB	
and (semiconductor chip circuit IC)).ab. and		
((compare comparing comparison		
compared) with (output result)) and		
714/719.ccls.		
	same (memory RAM ROM SRAM DRAM PROM) and (semiconductor IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor IC)).ab. parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC)).ab. parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC)).ab. and ((compare comparing comparison compared) with (output result)) parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and (semiconductor chip circuit IC)).ab. and (compare comparing comparison compared) with (output result)) and	same (memory RAM ROM SRAM DRAM PROM) and (semiconductor IC) and ((test testing tester tested) same (memory RAM (semiconductor IC)).ab. parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC)).ab. parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC)).ab. and ((compare comparing comparison compared) with (output result)) parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC)).ab. and ((compare comparing comparison compared) with (output result)) and

100	("6076136" "5047972" "4453209" "5512766"	USPAT	2004/08/10
	"5255383" "5561671" "5959692" "6237122"		13:52
	"5388074" "5717653" "5729500" "5732278"		
	"5838604" "6088291" "6246620" "5319395"		
	"5802587" "5818789" "6163832" "4327291"		
	"4384348" "4397000" "4562488" "4628497"	İ	
	"4864543" "4954991" "4964046" "5231673"		
	"5245585" "5313551" "5365485" "5497473"		·
	"5506806" "5544341" "5586282" "6055615"		
	"4319084" "4387308" "4424587" "4443845"		
	"4458332" "4532549" "4572974" "4580039"		
	"4623990" "4893298" "4914575" "4942593"		
	"4945518" "4959822").pn.		
	("5237670" "5287327" "5313594" "5339276"		
	"5430688" "5438559" "5444858" "5477494"		
	"5500848" "5502488" "5519498" "5521879"		
	"5535353" "5550996" "5577229" "5579267"		
	"5586299" "5592348" "5596731" "5615190"	i	
	"5715410" "5757809" "5818771" "5829015"		
	"5838895" "5841727" "5845314" "5886708"		
	"5912849" "5959935" "6011728" "6029211"		
	"6118742" "6181609" "6191992" "6341192"		
	"4242973" "4247921" "4270190" "4278838"		
	"4322752" "4323980" "4325135" "4326282"		
	"4335405" "4366535" "4373168" "4387449"		
	"4392198" "4397008").pn.		

-	50	("6173425"	USPAT	2004/08/10
-	30	"4975876"	JOPAT	16:41
		"5193092"		10:41
		"5561671"		
		"5961653"		
		"4320881"		
		"4429388"		
		"4493073"		
		"4809231"		
		"4903265"		
*		"4951254"		
		"5255271"		
-		"5331644"		
		"5424984" "5426940"		
		"5436910" "F623677"		
		"5633877"		
		"5691951"		
		"5691950"		
		"5818772" "585 4765"		
		"5854765"		
		"5898704"		
		"5920573"		
		"5968194"		
		"5982681"		
	•	"6108252"		
		"6237122"		
		"6243841"		
		"4268911"		
		"4287594"		
		"4297680"		
		"4312067"		
		"4339801"		
		"4409635"		
		RE31582		
-		"4482953"		
		"4504929"		
		RE31864		
		"4510580"		
		"4519077"		
		"4574068"		
		"4580230"		
		"4601032"		
		"4622652"		
		"4622647"		
		"4626769"		,
		"4628443"		
		"4768194"		
		"4862418"		
		"4872168"		
	L	"4897817").pn.	<u></u>	

•	51	parallel with (test testing tester tested)	USPAT;	2004/08/10
		same (memory RAM ROM SRAM DRAM	US-PGPUB;	16:41
		PROM) and (semiconductor chip circuit IC)	EPO; JPO;	
		and ((test testing tester tested) same	DERWENT;	
		(memory RAM ROM SRAM DRAM PROM)	IBM_TDB	
		and (semiconductor chip circuit IC)).ab. and		
		((compare comparing comparison		
		compared) with (output result)) and		
		714/719.ccls.		

•	50	("6173425"	USPAT	2004/08/10
		"4975876"		16:42
		"5193092"	į	
		"5561671"		
		"5961653"		
		"4320881"		
		"4429388"		
		"4493073"		
		"4809231"		
		"4903265"		
		"4951254"		
		"5255271"		
		"5331644"		
		"5424984"		
		"5436910"		
		"5633877"		
		"5691951"		
		"5691950"		
		"5818772"		
		"5854765"		
		"5898704"		
		"5920573" "F069404"		
		"5968194"		
1		"5982681"		
		"6108252"		
		"6237122"		
		"6243841"		
		"4268911"		
		"4287594"		
		"4297680"		
		"4312067"		
		"4339801"		
		"4409635"		
		RE31582		
		"4482953"		
		"4504929"		
		RE31864		
į		"4510580"		
		"4519077"		
		"4574068"		
		"4580230"		
		"4601032"		
		"4622652"		
		"4622647"		
		"4626769"		
		"4628443"		
j		"4768194"		
		"4862418"		
		"4872168"		
		"4897817").pn.		

"6237122" "6243841" "4268911" "4287594" "4297680" "4312067" "4339801" "4409635" RE31582 "4482953" "4504929" RE31864 "4510580" "4519077" "4574068" "4580230" "4601032" "4622652" "4622647" "4626769"		0	(parallel with (test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC) and ((test testing tester tested) same (memory RAM ROM SRAM DRAM PROM) and (semiconductor chip circuit IC)).ab. and ((compare comparing comparison compared) with (output result)) and 714/719.ccls. ) and (("6173425" "4975876" "5193092" "5561671" "5961653" "4320881" "4429388" "4493073" "4809231" "4903265" "4951254" "5255271" "5331644" "5436910" "5633877" "5691951" "5691950" "5818772" "5854765" "5898704" "5920573" "5968194" "5982681" "6108252"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/10 16:42
"5982681" "6108252" "6237122" "6243841" "4268911" "4287594" "4297680" "4312067" "4339801" "4409635" RE31582 "4482953" "4504929" RE31864 "4510580" "4519077" "4574068" "4580230" "4601032" "4622652" "4622652"			"5818772" "5854765" "5898704"		
"4268911" "4287594" "4297680" "4312067" "4339801" "4409635" RE31582 "4482953" "4504929" RE31864 "4510580" "4519077" "4574068" "4580230" "4601032" "4622652" "4622647"			"5982681" "6108252" "6237122"	:	
"4409635" RE31582 "4482953" "4504929" RE31864 "4510580" "4519077" "4574068" "4580230" "4601032" "4622652" "4622647"			"4287594" "4297680" "4312067"		
"4510580" "4519077" "4574068" "4580230" "4601032" "4622652" "4622647"			"4409635" RE31582 "4482953"		
"4601032" "4622652" "4622647"	,		"4510580" "4519077" "4574068"		
			"4601032" "4622652" "4622647"		

-	10	(("6173425"	USPAT;	2004/08/10
		"4975876"	US-PGPUB;	16:42
		"5193092"	EPO; JPO;	
		"5561671"	DERWENT;	
		"5961653"	IBM_TDB	
		"4320881"		
		"4429388"		1
		"4493073"		
		"4809231"		
		"4903265"		
		"4951254"		
		"5255271"		
		"5331644"		
		"5424984"		
		"5436910"		
		"5633877"		
		"5691951"	1	
		"5691950"		
		"5818772"		
		"5854765"		
		"5898704"		
		"5920573" "F000404"		-
		"5968194" "5968194"		
		"5982681"		
ľ		"6108252"		
		"6237122" "0043044"		
		"6243841" "4268044"		
		"4268911"		
		"4287594" "4297680"		
		"4312067"		
		"4339801"		
		"4409635"		
		RE31582		
		"4482953"		
		"4504929"		
		RE31864		
		"4510580"		
		"4519077"		
		"4574068"		
		"4580230"		
		"4601032"		
		"4622652"		
		"4622647"		
		"4626769"		
1		"4628443"		
1		"4768194"		
		"4862418"		·
		"4872168"		
		"4897817").pn. ) and (semiconductor chip		
		circuit IC) and ((test testing tester tested)		
		same (memory RAM ROM SRAM DRAM		
		PROM) and (semiconductor chip circuit		
·		IC)).ab. and ((compare comparing	1	1

-	12	(britt and james).in.	USOCR	2004/08/11
				14:24
-	104	(britt).in.	USOCR	2004/08/11
				14:28
-	30320	(britt).in. hair	USOCR	2004/08/11
				14:25
-	2	(britt).in. and hair	USOCR	2004/08/11
				14:26
-	414297	(britt).in. and new york	USOCR	2004/08/11
				14:28
-	13	(britt).in. and (new adj york)	USOCR	2004/08/11
				14:29
-	345	memory and (test testing tested tester) and	USPAT;	2004/08/12
		(compare comparing comparison compared)	US-PGPUB;	17:41
		and (select selection selector selecting	EPO; JPO;	
		selected) and ((compare comparing	DERWENT;	
		comparison compared) with (each other))	IBM_TDB	
		and decod\$		0
-	154	memory and (test testing tested tester) and	USPAT;	2004/08/12
		(compare comparing comparison compared)	US-PGPUB;	17:43
		and (select selection selector selecting	EPO; JPO;	
		selected) and ((compare comparing	DERWENT;	
		comparison compared) with (each other))	IBM_TDB	
		and decod\$ and (multiplexer multiplexor		
		MUX)		
-	230	714/719.ccor.	USPAT;	2004/08/12
			US-PGPUB;	17:44
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	119	714/719.ccor. and decod\$	USPAT;	2004/08/12
		·	US-PGPUB;	17:44
			EPO; JPO;	
			DERWENT;	1
			IBM_TDB	2004/09/46
-	17	714/719.ccor. and decod\$ and MUX	USPAT;	2004/08/16
			US-PGPUB;	11:03
			EPO; JPO;	
			DERWENT;	
1	_	- 47700F	IBM_TDB USPAT;	2004/08/13
-	2	5475695.pn.	•	18:42
			US-PGPUB; EPO; JPO;	10:42
			DERWENT;	
			IBM_TDB	
		EATEGOE LIDDA	USPAT	2004/08/13
-	41	5475695.URPN.	USFAI	18:52
	_	EATECOE LIBBNI and simplified	USPAT	2004/08/13
-	6	5475695.URPN. and signature	USFAI	18:52
	1		L	10.32